

ACTIVE (DIGITAL) DELAY LINES

A01 SERIES (SINGLE DELAY)

A03 SERIES (TRIPLE DELAY)



FEATURES

- Economical cost, prompt delivery!
- Wide range of values, 10nS to 500nS.
- TTL compatible
- Operating temperature: 0°C to 70°C
- Single output SIP delay line now available-- consult factory for data sheet on SA01 Series

OPTIONS

- Non-standard delay times
- ECL and high speed CMOS available
- Increased operating temperature range
- Tighter tolerances, faster rise times
- Trailing edge measurement
- Low power design
- Military screening per MIL-D-83532

Low cost solution for single or triple delays!

RCD's digital delay lines have been designed to provide precise fixed delays with all the necessary drive and pick-off circuitry. All inputs and outputs are schottky-type and require no additional components to achieve specified delays. Encapsulated construction utilizes a molded DIP case designed to meet or exceed all applicable environmental requirements of MIL-D-23859. Type A01 features a single fixed delay time, whereas type A03 features three isolated delays.

TYPE A01 Single Delay Line

Delay Time (nSec)	Rise Time (Max.)
10±1.5	4nS
20±1.5	4nS
30±2	4nS
40±2	4nS
50±2.5	4nS
60±3	4nS
70±3.5	4nS
80±4	4nS
90±4.5	4nS
100±5	4nS
125±6.2	4nS
150±7.5	4nS
175±8.7	4nS
200±10	4nS
250±12.5	4nS
300±15	4nS
350±17.5	4nS
400 ±20	4nS
450±22.5	5nS
500±25	5nS

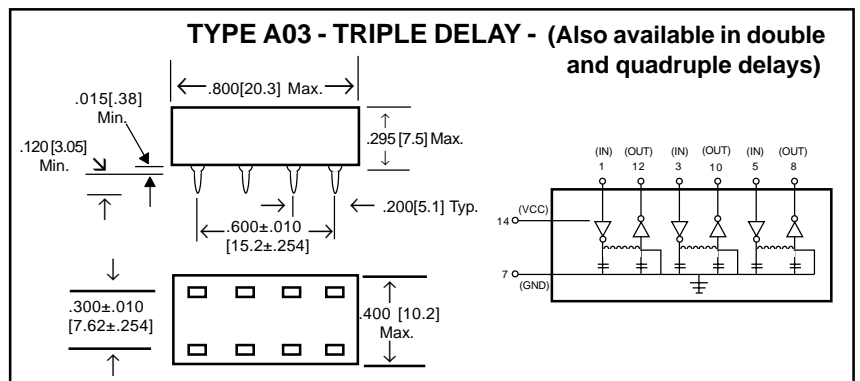
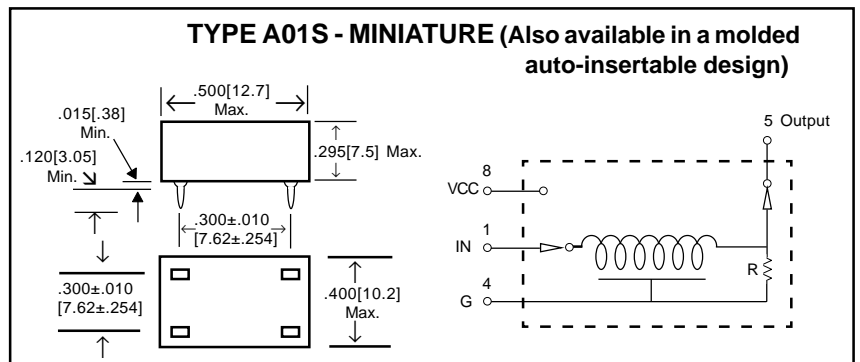
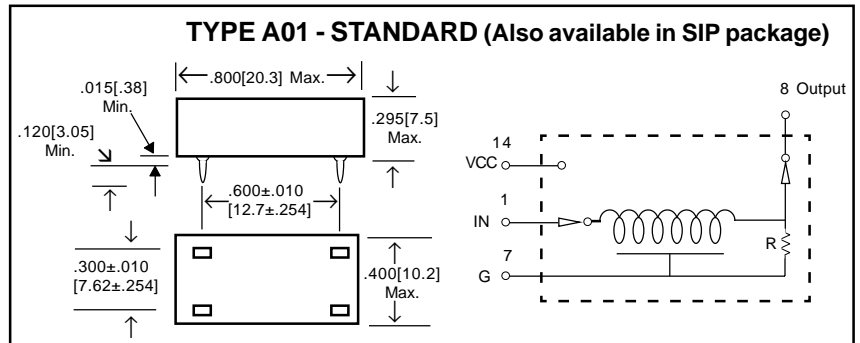
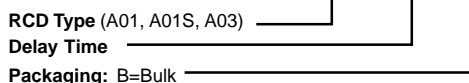
TYPE A03 Triple Delay Line

Delay Time (nSec)*	Rise Time (Max.)
10±1.5	4nS
20±1.5	4nS
30±2	4nS
40±2	4nS
50±2.5	4nS
60±3	4nS
70±3.5	4nS
80±4	4nS
90±4.5	4nS
100±5	4nS

* Available up to 250nS on special order.

P/N DESIGNATION:

A01 - 100nS - B



TEST CONDITIONS @ 25°C

- 1.) Input test pulse voltage: 3.2V
- 2.) Input pulse width: 3x the total delay
- 3.) Input rise time: 2.0nSec
- 4.) Delay measured at 1.5V on leading edge only with no loads on output.
- 5.) Rise time measured from 0.75V to 2.4V.
- 6.) Pulse period: 3x pulse width minimum